

Application/Control No.	Applicant(s)/Patent under Reexamination TAKAYAMA ET AL.	
10/735,886		
Examiner	Art Unit	
Nitin Parekh	2811	

SEARCHED					
Class	Subclass	Date	Examiner		
257	Updated 758, 761- 763, 753	6/12/2006	NP		
			_		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
			-		
	B (see text history)	6/12/2006	NP		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East 2.0.3, USPTO, JPO, EPO, IBM Tech. Discl., Derwent	6/12/2006	NP,	
Text search		NP	
<u></u>			